



SIDC30D60E6

Fast switching diode chip in EMCON-Technology

FEATURES:

- 600V EMCON technology 70 μm chip
- soft , fast switching
- low reverse recovery charge
- small temperature coefficient

This chip is used for:

EUPEC power modules and discrete devices



Applications:

• SMPS, resonant applications, drives

| Chip Type | V_R | I _F | Die Size | Package | Ordering Code |
|---------------|-----------------|----------------|---------------------------|--------------|---------------|
| SIDC30D60E6 | 600V | 75A | 5.5 x 5.5 mm ² | sawn on foil | C67047-A4679- |
| 0.2 0002 0020 | 0.0 × 0.0 11111 | Jawii dii idii | A001 | | |

MECHANICAL PARAMETER:

| MEGHANIGAE I ANAMETEN: | | | | | |
|---------------------------------|---|-----------------|--|--|--|
| Raster size | 5.5 x 5.5 | | | | |
| Area total / active | 30.25 / 23.33 | mm ² | | | |
| Anode pad size | 4.78 x 4.78 | | | | |
| Thickness | 70 | μm | | | |
| Wafer size | 150 | mm | | | |
| Flat position | 180 | deg | | | |
| Max. possible chips per wafer | 482 pcs | | | | |
| Passivation frontside | Photoimide | | | | |
| Anode metallisation | 3200 nm AlSiCu | | | | |
| Cathode metallisation | 1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding | | | | |
| Die bond | electrically conductive glue or solder | | | | |
| Wire bond | AI, ≤500μm | | | | |
| Reject Ink Dot Size | Ø 0.65mm ; max 1.2mm | | | | |
| Recommended Storage Environment | store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C | | | | |



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Maximum Ratings

| Parameter | Symbol | Condition | Value | Unit |
|---|----------------------------|--------------------------------|---------|------|
| Repetitive peak reverse voltage | V_{RRM} | | 600 | V |
| Continuous forward current limited by T_{jmax} | I _F | | 75 | |
| Single pulse forward current (depending on wire bond configuration) | I _{FSM} | $t_P = 10 \; ms \; sinusoidal$ | tbd | Α |
| Maximum repetitive forward current limited by T _{jmax} | I _{FRM} | | 225 | |
| Operating junction and storage temperature | $T_{\rm j}$, $T_{ m stg}$ | | -55+150 | °C |

Static Electrical Characteristics (tested on chip), T_j =25 °C, unless otherwise specified

| Parameter | Symbol | Cond | Value | | | Unit | |
|---------------------------------|----------|----------------------|-----------------------------|------|------|------|-------|
| raiailletei | Syllibol | Conditions | | min. | Тур. | max. | Oilit |
| Reverse leakage current | I_{R} | V _R =600V | <i>T_j</i> =25 °C | | | 27 | μΑ |
| Cathode-Anode breakdown Voltage | V_{Br} | I _R =4mA | <i>T_j</i> =25°C | 600 | | | V |
| Forward voltage drop | V_F | I _F =75A | <i>T_j</i> =25°C | | 1.25 | | V |

Dynamic Electrical Characteristics, at $T_j = 25$ °C, unless otherwise specified, tested at component

| Parameter | Symbol Con | | tions | Value | | | Unit |
|---|-----------------------|---|-----------------------|-------|------|------|------|
| raiailletei | Syllibol | Condi | Conditions | | Тур. | max. | |
| Reverse recovery time | t _{rr1} | I _F =75A | $T_j = 25$ °C | | tbd | | |
| | t _{rr2} | $di/dt=3000A/ms$ $V_R=300V$ | $T_j = 125$ °C | | | | ns |
| Peak recovery current | I _{RRM1} | I _F =75A | $T_j = 25$ °C | | 104 | | Α |
| | I _{RRM2} | $\begin{array}{l} di/dt = 3000 A/ms \\ V_R = 300 V \end{array}$ | $T_j = 125$ °C | | 121 | | 7^ |
| Reverse recovery charge | Q _{rr1} | I _F =75A | T _j =25°C | | 5.2 | | |
| | Q _{rr2} | $di/dt=3000A/ms$ $V_R=300V$ | T _j =125°C | | 8.6 | | μC |
| Peak rate of fall of reverse recovery current | di _{rr1} /dt | $I_F=75A$ di/dt=3000A/ms $V_R=300V$ | T _j =25°C | | tbd | | A/μs |
| | di _{rr2} /dt | | T _j =125°C | | | | |
| Softness | S1 | I _F =75A di/dt=3000A/ ms | T _j =25°C | | tbd | | 1 |
| | S2 | $V_R = 3000A/ms$ | T _j =125°C | | _ | | |

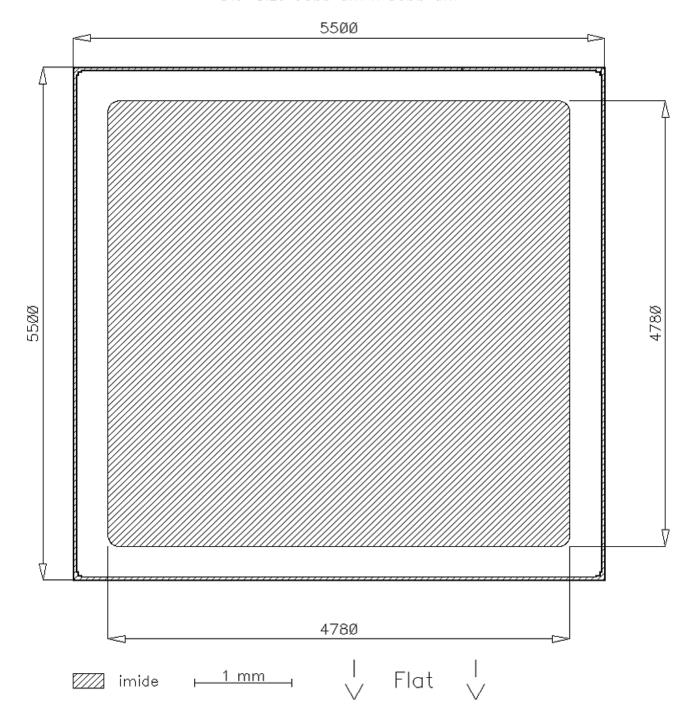


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CHIP DRAWING:

L418B1

Die-Size 5500 um x 5500 um



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Preliminary

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FURTHER ELECTRICAL CHARACTERISTICS:

| This chip data sheet refers to the device data sheet | INFINEON TECHNOLOGIES / EUPEC | tbd |
|--|----------------------------------|-----|
| Description: | | |
| AQL 0,65 for visual inspection according to | failure catalog | |
| Electrostatic Discharge Sensitive Device ac | cording to MIL-STD 883 | |

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